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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

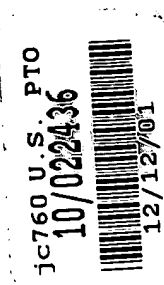
In re application of: Timothy B. Cowles and
Christian N. Mohr

Serial No.:

Filed: December 12, 2001

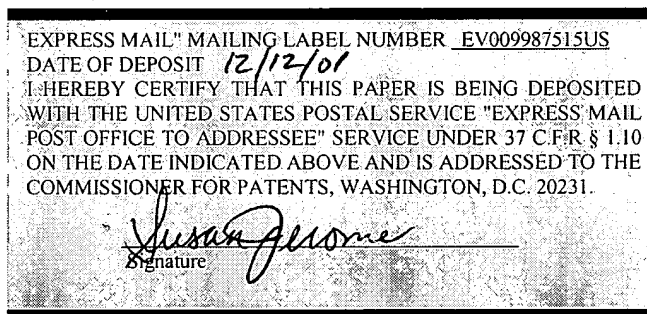
For: CIRCUIT AND METHOD FOR TEST
AND REPAIR

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§ Group Art Unit:
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§ Examiner:
§
§ Atty. Docket: 00-0058.02
§
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INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents
Washington, D.C. 20231



Dear Sir:

In compliance with the duty of disclosure under 37 C.F.R. § 1.56, Applicants respectfully request that this Information Disclosure Statement be entered and that the references listed on the attached Form PTO-1449 be considered by the Examiner and made of record.. Copies of the listed references are enclosed for the convenience of the Examiner.

In accordance with 37 C.F.R. § 1.97(b), this Information Disclosure Statement is not to be construed as a representation that a search has been made or that no other possible material information as defined in 37 C.F.R. § 1.56(a) exists.

The following references are submitted for the Examiner's review:

U.S. Patents

<u>U.S. Patent No.</u>	<u>Issue Date</u>	<u>Inventor</u>
6,154,851	11/28/00	Sher et al.
6,154,398	11/28/00	Cutter et al.
6,145,092	11/07/00	Beffa et al.
6,144,593	11/07/00	Cowles et al.
6,130,834	10/10/00	Mullarkey et al.
6,119,251	09/12/00	Cloud et al.
6,104,645	08/15/00	Ong et al.
6,088,282	07/11/00	Loughmiller et al.
5,959,929	09/28/99	Cowles et al.
5,917,764	06/29/99	Ohsawa et al.
5,910,921	06/08/99	Beffa et al.
5,883,843	03/16/99	Hii et al.
5,724,282	03/03/98	Loughmiller et al.
5,655,105	08/05/97	McLaury

Other References

Cowles, Timothy B., "Circuit and Method for Test and Repair," application serial No. 09/864,682, filed May 24, 2001.

Cowles, Timothy B., "Circuit and Method for Test and Repair," application serial No. 09/810,366, filed March 15, 2001.

Micron Technology, Inc.; "Synchronous DRAM" Data Sheets; 128Mb: x4, x8, x16 SDRAM, 128MSDRAM_ Rev B_, p65; Pub. 10/00, pp. 1-58.

Micron Technology, Inc.; "Synchronous DRAM" Data Sheets; 128Mb: x32 SDRAM, 128Mb: x32 DRAM, 128MbSDRAMx32, p65 – Rev. 9/00, pp. 1-52.

As this information is being submitted within three months of the date of filing of the application, Applicants understand that no fee or certification is required for the submission and consideration of this information at this time.

If there are any matters which may be resolved or clarified through telephone interview, the Examiner is respectfully requested to contact Applicants' undersigned attorney at the number indicated.

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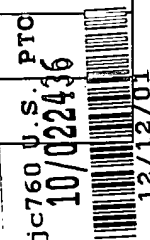
A Form PTO-1449 is enclosed herewith.

Respectfully submitted,

Date: Charles Brantley
12/12/01

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FORM: PTO-1449 (REV: 7-80)	U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE	Atty Docket No: 00-0058.02	Serial No:
INFORMATION DISCLOSURE STATEMENT BY APPLICANT (37 CFR 1.98(b)) (use several sheets if necessary)		Applicant: Timothy B. Cowles et al.	
		Filing Date: December 12, 2001	Group:

**U.S. PATENT DOCUMENTS**

Examiner Initial	Document Number	Date	Name	Class	Subclass	
	AA	6,154,851	11/28/00	Sher et al.	714	005
	AB	6,154,398	11/28/00	Cutter et al.	365	200
	AC	6,145,092	11/07/00	Beffa et al.	714	007
	AD	6,144,593	11/07/00	Cowles et al.	365	200
	AE	6,130,834	10/10/00	Mullarkey et al.	365	096
	AF	6,119,251	09/12/00	Cloud et al.	714	718
	AG	6,104,645	08/15/00	Ong et al.	365	200
	AH	6,088,282	07/11/00	Loughmiller et al.	365	225.7
	AI	5,959,929	09/28/99	Cowles et al.	365	230.03
	AJ	5,917,764	06/29/99	Ohsawa et al.	365	200
	AK	5,910,921	06/08/99	Beffa et al.	365	201
	AL	5,883,843	03/16/99	Hii et al.	365	201
	AM	5,724,282	03/03/98	Loughmiller et al.	365	096
	AN	5,655,105	08/05/97	McLaury	395	496

FOREIGN PATENT DOCUMENTS

Examiner Initial	Document Number	Date	Country	Class	Subclass	Translation	
						Yes	No
	AO					<input type="checkbox"/>	<input type="checkbox"/>
	AP					<input type="checkbox"/>	<input type="checkbox"/>
	AQ					<input type="checkbox"/>	<input type="checkbox"/>

Initial

OTHER ART (including author, title, date, pertinent pages, etc.)

	AR		Cowles, Timothy B., "Circuit and Method for Test and Repair," application serial No. 09/864,682, filed May 24, 2001
	AS		Cowles, Timothy B., "Circuit and Method for Test and Repair," application serial No. 09/810,366, filed March 15, 2001.
	AT		Micron Technology, Inc.; "Synchronous DRAM" Data Sheets; 128Mb: x4, x8, x16 SDRAM, 128MSDRAM_ Rev B_, p65; Pub. 10/00, pp. 1-58.
	AU		Micron Technology, Inc.; "Synchronous DRAM" Data Sheets; 128Mb: x32 SDRAM, 128Mb: x32 DRAM, 128MbSDRAMx32, p65 - Rev. 9/00, pp. 1-52.

Examiner:	Date Considered:
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EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication with applicant.